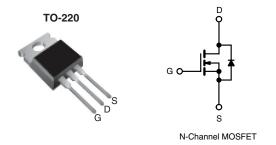


Power MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	450			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.63		
Q _g (Max.) (nC)	80			
Q _{gs} (nC)	12			
Q _{gd} (nC)	41			
Configuration	Single			



FEATURES

- · Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provides the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION		
Package	TO-220	
Load (Dh.) free	IRF744PbF	
Lead (Pb)-free	SiHF744-E3	
SnPb	IRF744	
	SiHF744	

ABSOLUTE MAXIMUM RATINGS \top	$_{\rm C}$ = 25 $^{\circ}$ C, unless otherw	ise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Gate-Source Voltage	V _{GS}	± 20	V		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$		8.8	А	
	V_{GS} at 10 V $T_C = 100 ^{\circ}C$	I _D	5.6		
Pulsed Drain Current ^a	I _{DM}	35	1		
Linear Derating Factor			1.0	W/°C	
Single Pulse Avalanche Energy ^b	E _{AS}	540	mJ		
Repetitive Avalanche Current ^a	I _{AR}	8.8	А		
Repetitive Avalanche Energy ^a	E _{AR}	13	mJ		
Maximum Power Dissipation	T _C = 25 °C	P_{D}	125	W	
Peak Diode Recovery dV/dtc		dV/dt	3.5	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	00	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	°C	
Mounting Torque	C 20 or M2 corour		10	lbf ⋅ in	
	6-32 or M3 screw		1.1	N · m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 12 \,^{\circ}\text{mH}$, $R_G = 25 \,^{\circ}\Omega$ $I_{AS} = 8.8 \,^{\circ}\text{A}$ (see fig. 12).
- c. $I_{SD} \le 8.8$ A, $dV/dt \le 200$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0	

PARAMETER	SYMBOL	TEST	TEST CONDITIONS		TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		0.59	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20		-	-	± 100	nA
Zero Gate Voltage Drain Current	1	V _{DS} = 4	V _{DS} = 450 V, V _{GS} = 0 V		-	25	
Zero Gate Voltage Drain Gurrent	I _{DSS}	$V_{DS} = 360 \text{ V}, \text{ V}$	V _{GS} = 0 V, T _J = 125 °C	1	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	$I_D = 5.3 A^b$	1	-	0.63	Ω
Forward Transconductance	9 _{fs}	$V_{DS} = 5$	V _{DS} = 50 V, I _D = 5.3 A ^b		-	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V		1	1400	-	pF
Output Capacitance	C _{oss}	V	V _{DS} = 25 V f = 1.0 MHz, see fig. 5		370	-	
Reverse Transfer Capacitance	C_{rss}	f = 1.0			140	-	
Total Gate Charge	Q_g			-	-	80	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$I_D = 8.8 \text{ A}, V_{DS} = 360 \text{ V},$	1	-	12	
Gate-Drain Charge	Q_{gd}	1	see fig. 6 and 13 ^b	-	-	41	
Turn-On Delay Time	t _{d(on)}		-	-	8.7	-	
Rise Time	t _r	V _{DD} = 2	V _{DD} = 225 V, I _D = 8.8 A		28	-	- ns
Turn-Off Delay Time	t _{d(off)}	$R_G = 9.1 \Omega$, $R_D = 25 \Omega$, see fig. 10^b		-	58	-	
Fall Time	t _f			-	27	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	n 1
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	8.8	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	35	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 8.8 A, V _{GS} = 0 V ^b		ı	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	$T_J = 25 ^{\circ}\text{C}, I_F = 8.8 \text{A}, \text{dI/dt} = 100 \text{A/}\mu\text{s}^b$		-	490	740	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.2	4.8	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

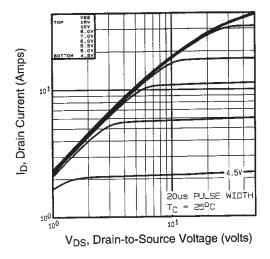


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

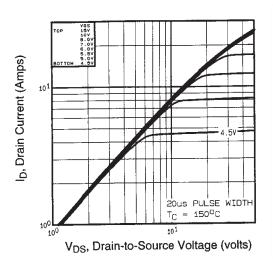


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

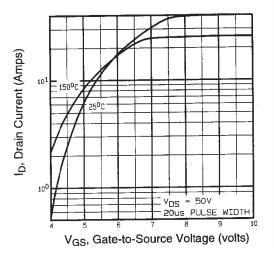


Fig. 3 - Typical Transfer Characteristics

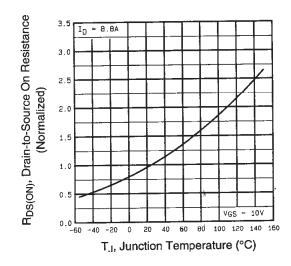


Fig. 4 - Normalized On-Resistance vs. Temperature



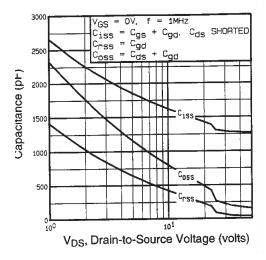


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

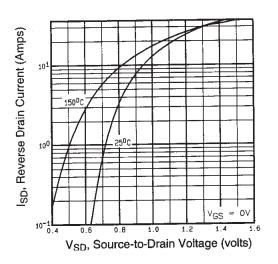


Fig. 7 - Typical Source-Drain Diode Forward Voltage

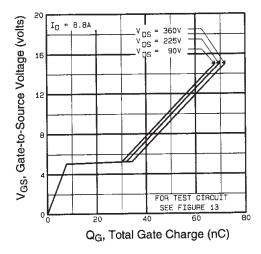


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

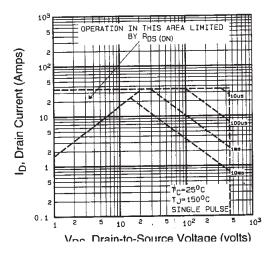


Fig. 8 - Maximum Safe Operating Area





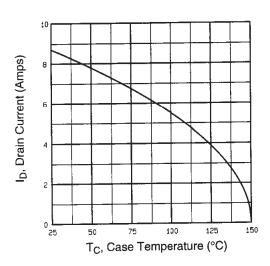


Fig. 9 - Maximum Drain Current vs. Case Temperature

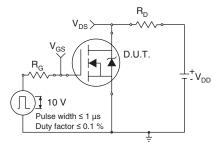


Fig. 10a - Switching Time Test Circuit

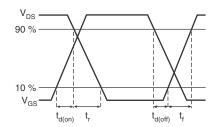


Fig. 10b - Switching Time Waveforms

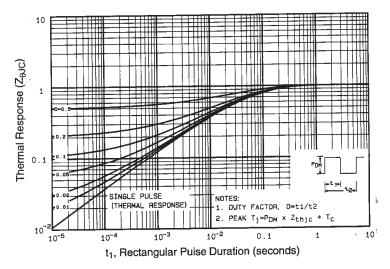


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

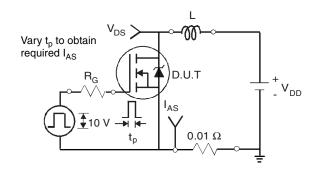


Fig. 12a - Unclamped Inductive Test Circuit

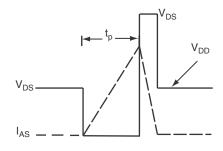


Fig. 12b - Unclamped Inductive Waveforms



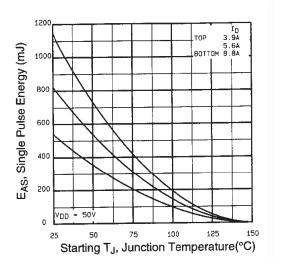


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

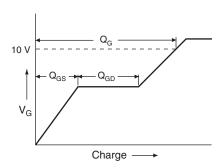


Fig. 13a - Basic Gate Charge Waveform

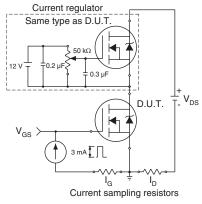
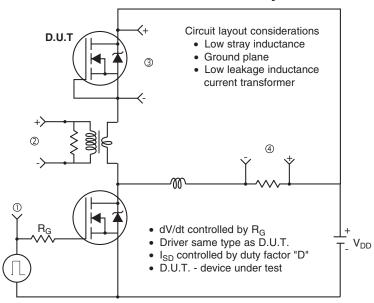
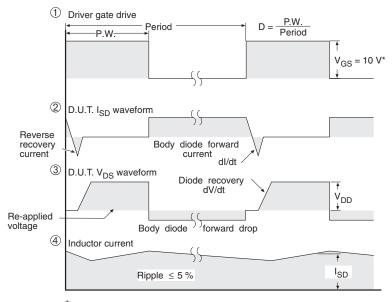


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

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